Ghaith Bany Hamad

List of Publications by Year in descending order

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#	Article	IF	CITATIONS
1	Towards Safe and Robust Closed-Loop Artificial Pancreas Using Improved PID-Based Control Strategies. IEEE Transactions on Circuits and Systems I: Regular Papers, 2021, 68, 3147-3157.	5.4	12
2	Routing and Scheduling of Time-Triggered Traffic in Time-Sensitive Networks. IEEE Transactions on Industrial Informatics, 2020, 16, 4525-4534.	11.3	82
3	Towards Safe and Robust Closed-Loop Artificial Pancreas Using Adaptive Weighted PID Control Strategy. , 2020, , .		3
4	Towards System Level Security Analysis of Artificial Pancreas Via UPPAAL-SMC., 2019,,.		5
5	Probabilistic High-Level Estimation of Vulnerability and Fault Mitigation of Critical Systems Using Fault-Mitigation Trees (FMTs). , 2019, , .		O
6	Reliability Analysis of TSN Networks Under SEU Induced Soft Error Using Model Checking., 2019,,.		3
7	Towards an Accurate Probabilistic Modeling and Statistical Analysis of Temporal Faults via Temporal Dynamic Fault-Trees (TDFTs). IEEE Access, 2019, 7, 29264-29276.	4.2	12
8	New Insights Into Soft-Faults Induced Cardiac Pacemakers Malfunctions Analyzed at System-Level via Model Checking. IEEE Access, 2018, 6, 62107-62119.	4.2	2
9	Reliability Analysis of the SPARC V8 Architecture via Fault Trees and UPPAL-SMC. , 2018, , .		O
10	Fault-Resilient Topology Planning and Traffic Configuration for IEEE 802.1Qbv TSN Networks. , 2018, , .		26
11	Formal Methods Based Synthesis of Single Event Transient Tolerant Combinational Circuits. Journal of Electronic Testing: Theory and Applications (JETTA), 2017, 33, 607-620.	1.2	O
12	System-Level Analysis of the Vulnerability of Processors Exposed to Single-Event Upsets via Probabilistic Model Checking. IEEE Transactions on Nuclear Science, 2017, 64, 2523-2530.	2.0	6
13	System level SEUs propagation analysis via data flow-based reduction and quantitative model checking. , 2017, , .		O
14	Characterizing, modeling, and analyzing soft error propagation in asynchronous and synchronous digital circuits. Microelectronics Reliability, 2015, 55, 238-250.	1.7	17
15	Modeling, analyzing, and abstracting single event transient propagation at gate level. , 2014, , .		9
16	New Insights Into the Single Event Transient Propagation Through Static and TSPC Logic. IEEE Transactions on Nuclear Science, 2014, 61, 1618-1627.	2.0	15
17	Identification of soft error glitch-propagation paths: Leveraging SAT solvers. , 2012, , .		3
18	SEGP-Finder: Tool for identification of Soft Error Glitch-Propagating paths at gate level., 2011,,.		2